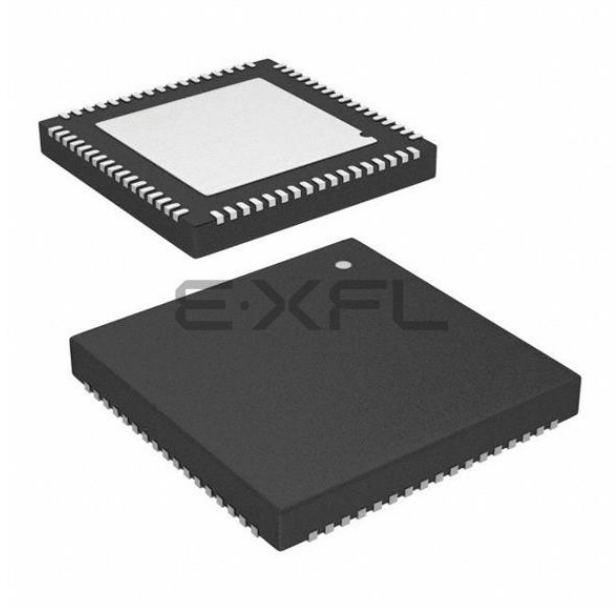

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Applications of "Embedded - Microcontrollers"

Details	
Product Status	Obsolete
Core Processor	8051
Core Size	8-Bit
Speed	67MHz
Connectivity	EBI/EMI, I²C, LINbus, SPI, UART/USART, USB
Peripherals	CapSense, DMA, LCD, POR, PWM, WDT
Number of I/O	38
Program Memory Size	32KB (32K x 8)
Program Memory Type	FLASH
EEPROM Size	1K x 8
RAM Size	4K x 8
Voltage - Supply (Vcc/Vdd)	1.71V ~ 5.5V
Data Converters	A/D 16x20b; D/A 2x8b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	68-VFQFN Exposed Pad
Supplier Device Package	68-QFN (8x8)
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/cy8c3865lti-205t

Figure 2-3. 48-pin SSOP Part Pinout

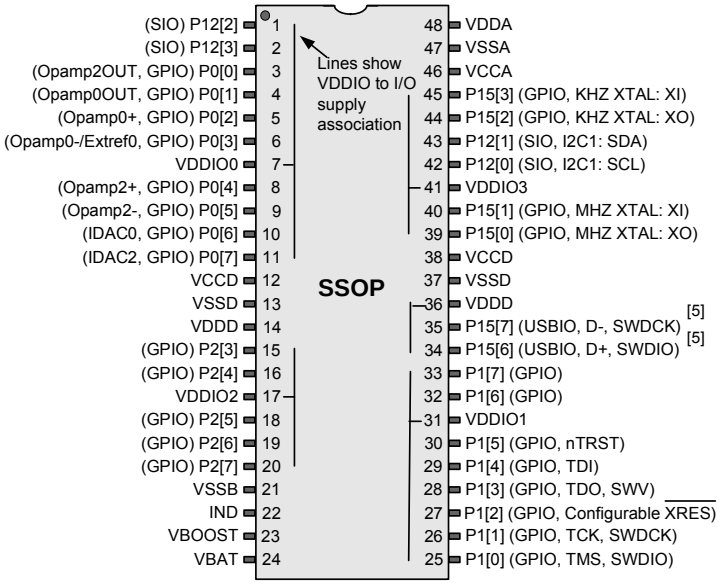
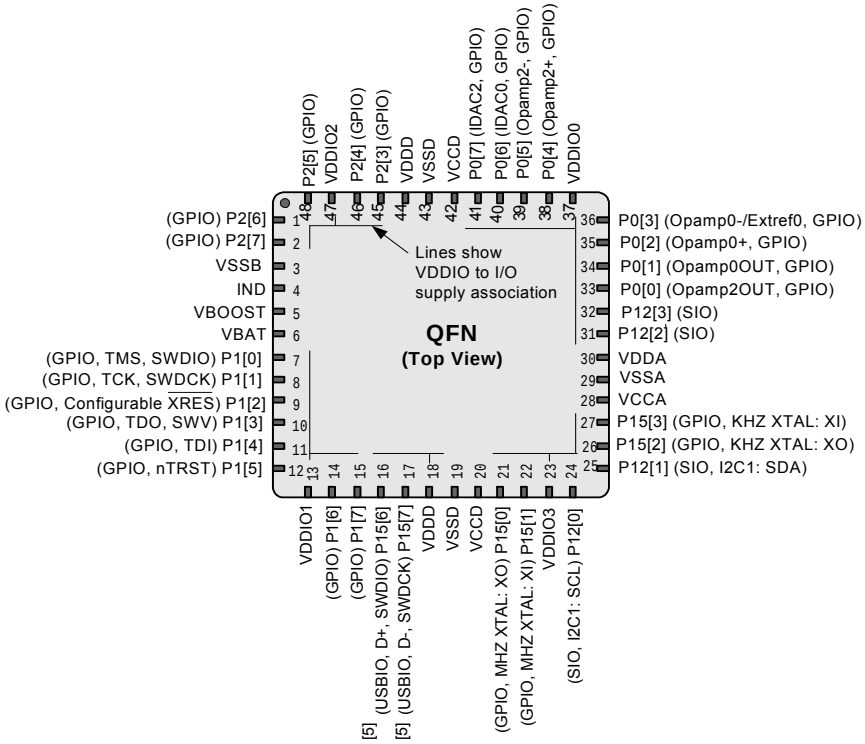


Figure 2-4. 48-pin QFN Part Pinout[6]



Notes

5. Pins are Do Not Use (DNU) on devices without USB. The pin must be left floating.
6. The center pad on the QFN package should be connected to digital ground (VSSD) for best mechanical, thermal, and electrical performance. If not connected to ground, it should be electrically floated and not connected to any other signal. For more information, see AN72845, Design Guidelines for QFN Devices.

Table 2-2 shows the pinout for the 72-pin CSP package. Since there are four V_{DDIO} pins, the set of I/O pins associated with any V_{DDIO} may sink up to 100 mA total, same as for the 100-pin and 68-pin devices.

Table 2-2. CSP Pinout

Ball	Name	Ball	Name	Ball	Name
G6	P2[5]	F1	VDDD	A5	VDDA
E5	P2[6]	E1	VSSD	A6	VSSD
F5	P2[7]	E2	VCCD	B6	P12[2]
J7	P12[4]	C1	P15[0]	C6	P12[3]
H6	P12[5]	C2	P15[1]	A7	P0[0]
J6	VSSB	D2	P3[0]	B7	P0[1]
J5	Ind	D3	P3[1]	B5	P0[2]
H5	VBOOST	D4	P3[2]	C5	P0[3]
J4	VBAT	D5	P3[3]	A8	VIO0
H4	VSSD	B4	P3[4]	D6	P0[4]
J3	XRES_N	B3	P3[5]	D7	P0[5]
H3	P1[0]	A1	VIO3	C7	P0[6]
G3	P1[1]	B2	P3[6]	C8	P0[7]
H2	P1[2]	A2	P3[7]	E8	VCCD
J2	P1[3]	C3	P12[0]	F8	VSSD
G4	P1[4]	C4	P12[1]	G8	VDDD
G5	P1[5]	E3	P15[2]	E7	P15[4]
J1	VIO1	E4	P15[3]	F7	P15[5]
F4	P1[6]	B1[10]	NC	G7	P2[0]
F3	P1[7]	B8[10]	NC	H7	P2[1]
H1	P12[6]	D1[10]	NC	H8	P2[2]
G1	P12[7]	D8[10]	NC	F6	P2[3]
G2	P15[6]	A3	VCCA	E6	P2[4]
F2	P15[7]	A4	VSSA	J8	VIO2

Figure 2-7 and Figure 2-8 show an example schematic and an example PCB layout, for the 100-pin TQFP part, for optimal analog performance on a two-layer board.

- The two pins labeled VDDD must be connected together.
- The two pins labeled VCCD must be connected together, with capacitance added, as shown in Figure 2-7 and Power System on page 31. The trace between the two VCCD pins should be as short as possible.
- The two pins labeled VSSD must be connected together.

For information on circuit board layout issues for mixed signals, refer to the application note, AN57821 - Mixed Signal Circuit Board Layout Considerations for PSoC® 3 and PSoC 5.

Note
10. These pins are Do Not Use (DNU); they must be left floating.

Table 4-4. Boolean Instructions *(continued)*

Mnemonic	Description	Bytes	Cycles
ANL C, /bit	AND complement of direct bit to carry	2	2
ORL C, bit	OR direct bit to carry	2	2
ORL C, /bit	OR complement of direct bit to carry	2	2
MOV C, bit	Move direct bit to carry	2	2
MOV bit, C	Move carry to direct bit	2	3
JC rel	Jump if carry is set	2	3
JNC rel	Jump if no carry is set	2	3
JB bit, rel	Jump if direct bit is set	3	5
JNB bit, rel	Jump if direct bit is not set	3	5
JBC bit, rel	Jump if direct bit is set and clear bit	3	5

4.3.1.5 Program Branching Instructions

The 8051 supports a set of conditional and unconditional jump instructions that help to modify the program execution flow. Table 4-5 shows the list of jump instructions.

Table 4-5. Jump Instructions

Mnemonic	Description	Bytes	Cycles
ACALL addr11	Absolute subroutine call	2	4
LCALL addr16	Long subroutine call	3	4
RET	Return from subroutine	1	4
RETI	Return from interrupt	1	4
AJMP addr11	Absolute jump	2	3
LJMP addr16	Long jump	3	4
SJMP rel	Short jump (relative address)	2	3
JMP @A + DPTR	Jump indirect relative to DPTR	1	5
JZ rel	Jump if accumulator is zero	2	4
JNZ rel	Jump if accumulator is nonzero	2	4
CJNE A,Direct, rel	Compare direct byte to accumulator and jump if not equal	3	5
CJNE A, #data, rel	Compare immediate data to accumulator and jump if not equal	3	4
CJNE Rn, #data, rel	Compare immediate data to register and jump if not equal	3	4
CJNE @Ri, #data, rel	Compare immediate data to indirect RAM and jump if not equal	3	5
DJNZ Rn,rel	Decrement register and jump if not zero	2	4
DJNZ Direct, rel	Decrement direct byte and jump if not zero	3	5
NOP	No operation	1	1

4.4 DMA and PHUB

The PHUB and the DMA controller are responsible for data transfer between the CPU and peripherals, and also data transfers between peripherals. The PHUB and DMA also control device configuration during boot. The PHUB consists of:

- A central hub that includes the DMA controller, arbiter, and router
- Multiple spokes that radiate outward from the hub to most peripherals

There are two PHUB masters: the CPU and the DMA controller. Both masters may initiate transactions on the bus. The DMA channels can handle peripheral communication without CPU intervention. The arbiter in the central hub determines which DMA channel is the highest priority if there are multiple requests.

4.4.1 PHUB Features

- CPU and DMA controller are both bus masters to the PHUB
- Eight multi-layer AHB bus parallel access paths (spokes) for peripheral access
- Simultaneous CPU and DMA access to peripherals located on different spokes
- Simultaneous DMA source and destination burst transactions on different spokes
- Supports 8-, 16-, 24-, and 32-bit addressing and data

Table 4-6. PHUB Spokes and Peripherals

PHUB Spokes	Peripherals
0	SRAM
1	IOs, PICU, EMIF
2	PHUB local configuration, Power manager, Clocks, IC, SWV, EEPROM, Flash programming interface
3	Analog interface and trim, Decimator
4	USB, CAN, I^2C, Timers, Counters, and PWMs
5	DFB
6	UDBs group 1
7	UDBs group 2

4.4.2 DMA Features

- 24 DMA channels
- Each channel has one or more transaction descriptors (TD) to configure channel behavior. Up to 128 total TDs can be defined
- TDs can be dynamically updated
- Eight levels of priority per channel
- Any digitally routable signal, the CPU, or another DMA channel, can trigger a transaction
- Each channel can generate up to two interrupts per transfer
- Transactions can be stalled or canceled
- Supports transaction size of infinite or 1 to 64 KB
- TDs may be nested and/or chained for complex transactions

4.4.3 Priority Levels

The CPU always has higher priority than the DMA controller when their accesses require the same bus resources. Due to the system architecture, the CPU can never starve the DMA. DMA channels of higher priority (lower priority number) may interrupt current DMA transfers. In the case of an interrupt, the current transfer is allowed to complete its current transaction. To ensure latency limits when multiple DMA accesses are requested simultaneously, a fairness algorithm guarantees an interleaved minimum percentage of bus bandwidth for priority levels 2 through 7. Priority levels 0 and 1 do not take part in the fairness algorithm and may use 100 percent of the bus bandwidth. If a tie occurs on two DMA requests of the same priority level, a simple round robin method is used to evenly share the allocated bandwidth. The round robin allocation can be disabled for each DMA channel, allowing it to always be at the head of the line. Priority levels 2 to 7 are guaranteed the minimum bus bandwidth shown in Table 4-7 after the CPU and DMA priority levels 0 and 1 have satisfied their requirements.

Table 4-7. Priority Levels

Priority Level	% Bus Bandwidth
0	100.0
1	100.0
2	50.0
3	25.0
4	12.5
5	6.2
6	3.1
7	1.5

When the fairness algorithm is disabled, DMA access is granted based solely on the priority level; no bus bandwidth guarantees are made.

4.4.4 Transaction Modes Supported

The flexible configuration of each DMA channel and the ability to chain multiple channels allow the creation of both simple and complex use cases. General use cases include, but are not limited to:

4.4.4.1 Simple DMA

In a simple DMA case, a single TD transfers data between a source and sink (peripherals or memory location). The basic timing diagrams of DMA read and write cycles are shown in Figure 4-1. For more description on other transfer modes, refer to the Technical Reference Manual.

6. System Integration

6.1 Clocking System

The clocking system generates, divides, and distributes clocks throughout the PSoC system. For the majority of systems, no external crystal is required. The IMO and PLL together can generate up to a 66 MHz clock, accurate to ±1 percent over voltage and temperature. Additional internal and external clock sources allow each design to optimize accuracy, power, and cost. Any of the clock sources can be used to generate other clock frequencies in the 16-bit clock dividers and UDBs for anything the user wants, for example a UART baud rate generator.

Clock generation and distribution is automatically configured through the PSoC Creator IDE graphical interface. This is based on the complete system's requirements. It greatly speeds the design process. PSoC Creator allows you to build clocking systems with minimal input. You can specify desired clock frequencies and accuracies, and the software locates or builds a clock that meets the required specifications. This is possible because of the programmability inherent in PSoC.

Key features of the clocking system include:

- Seven general purpose clock sources
  - 3- to 62-MHz IMO, ±1% at 3 MHz
  - 4- to 25-MHz external crystal oscillator (MHzECO)
  - Clock doubler provides a doubled clock frequency output for the USB block, see USB Clock Domain on page 30.
  - DSI signal from an external I/O pin or other logic
  - 24- to 67-MHz fractional PLL sourced from IMO, MHzECO, or DSI
  - 1-kHz, 33-kHz, 100-kHz ILO for WDT and sleep timer
  - 32.768-kHz external crystal oscillator (kHzECO) for RTC
- IMO has a USB mode that auto locks to the USB bus clock requiring no external crystal for USB (USB equipped parts only)
- Independently sourced clock in all clock dividers
- Eight 16-bit clock dividers for the digital system
- Four 16-bit clock dividers for the analog system
- Dedicated 16-bit divider for the bus clock
- Dedicated 4-bit divider for the CPU clock
- Automatic clock configuration in PSoC Creator

Table 6-1. Oscillator Summary

Source	Fmin	Tolerance at Fmin	Fmax	Tolerance at Fmax	Startup Time
IMO	3 MHz	±1% over voltage and temperature	62 MHz	±7%	13 µs max
MHzECO	4 MHz	Crystal dependent	25 MHz	Crystal dependent	5 ms typ, max is crystal dependent
DSI	0 MHz	Input dependent	33 MHz	Input dependent	Input dependent
PLL	24 MHz	Input dependent	67 MHz	Input dependent	250 µs max
Doubler	48 MHz	Input dependent	48 MHz	Input dependent	1 µs max
ILO	1 kHz	–50%, +100%	100 kHz	–55%, +100%	15 ms max in lowest power mode
kHzECO	32 kHz	Crystal dependent	32 kHz	Crystal dependent	500 ms typ, max is crystal dependent

Figure 6-1. Clocking Subsystem

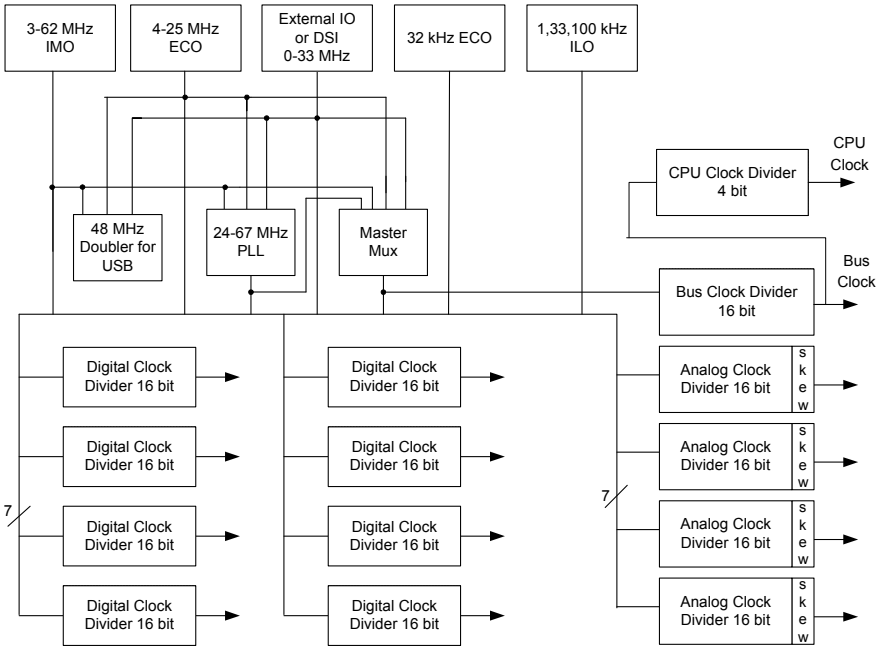
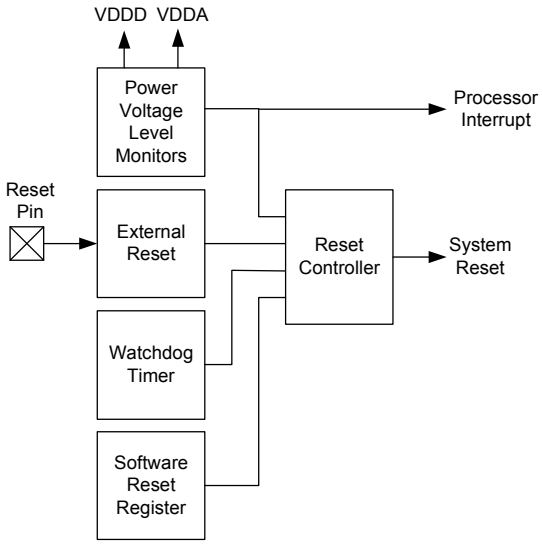


Figure 6-8. Resets



The term **device reset** indicates that the processor as well as analog and digital peripherals and registers are reset.

A reset status register shows some of the resets or power voltage monitoring interrupts. The program may examine this register to detect and report certain exception conditions. This register is cleared after a power-on reset. For details see the Technical Reference Manual.

6.3.1 Reset Sources

6.3.1.1 Power Voltage Level Monitors

- IPOR – Initial power-on reset

  At initial power on, IPOR monitors the power voltages VDDD, VDDA, VCCD and VCCA. The trip level is not precise. It is set to approximately 1 volt, which is below the lowest specified operating voltage but high enough for the internal circuits to be reset and to hold their reset state. The monitor generates a reset pulse that is at least 150 ns wide. It may be much wider if one or more of the voltages ramps up slowly.

  After boot, the IPOR circuit is disabled and voltage supervision is handed off to the precise low-voltage reset (PRES) circuit.

- PRES – Precise low voltage reset

  This circuit monitors the outputs of the analog and digital internal regulators after power up. The regulator outputs are compared to a precise reference voltage. The response to a PRES trip is identical to an IPOR reset.

  In normal operating mode, the program cannot disable the digital PRES circuit. The analog regulator can be disabled, which also disables the analog portion of the PRES. The PRES circuit is disabled automatically during sleep and hibernate modes, with one exception: During sleep mode the regulators are periodically activated (buzzed) to provide supervisory services and to reduce wakeup time. At these times the PRES circuit is also buzzed to allow periodic voltage monitoring.

- ALVI, DLVI, AHVI – Analog/digital low voltage interrupt, analog high voltage interrupt

  Interrupt circuits are available to detect when VDDA and VDDD go outside a voltage range. For AHVI, VDDA is compared to a fixed trip level. For ALVI and DLVI, VDDA and VDDD are compared to trip levels that are programmable, as listed in Table 6-5. ALVI and DLVI can also be configured to generate a device reset instead of an interrupt.

Table 6-5. Analog/Digital Low Voltage Interrupt, Analog High Voltage Interrupt

Interrupt	Supply	Normal Voltage Range	Available Trip Settings
DLVI	VDDD	1.71 V–5.5 V	1.70 V–5.45 V in 250 mV increments
ALVI	VDDA	1.71 V–5.5 V	1.70 V–5.45 V in 250 mV increments
AHVI	VDDA	1.71 V–5.5 V	5.75 V

The monitors are disabled until after IPOR. During sleep mode these circuits are periodically activated (buzzed). If an interrupt occurs during buzzing then the system first enters its wakeup sequence. The interrupt is then recognized and may be serviced.

The buzz frequency is adjustable, and should be set to be less than the minimum time that any voltage is expected to be out of range. For details on how to adjust the buzz frequency, see the TRM.

6.3.1.2 Other Reset Sources

- XRES – External reset

  PSoC 3 has either a single GPIO pin that is configured as an external reset or a dedicated XRES pin. Either the dedicated XRES pin or the GPIO pin, if configured, holds the part in reset while held active (low). The response to an XRES is the same as to an IPOR reset.

  After XRES has been deasserted, at least 10 µs must elapse before it can be reasserted.

  The external reset is active low. It includes an internal pull-up resistor. XRES is active during sleep and hibernate modes.

- SRES – Software reset

  A reset can be commanded under program control by setting a bit in the software reset register. This is done either directly by the program or indirectly by DMA access. The response to a SRES is the same as after an IPOR reset.

  Another register bit exists to disable this function.

- WRES – Watchdog timer reset

  The watchdog reset detects when the software program is no longer being executed correctly. To indicate to the watchdog timer that it is running correctly, the program must periodically reset the timer. If the timer is not reset before a user-specified amount of time, then a reset is generated.

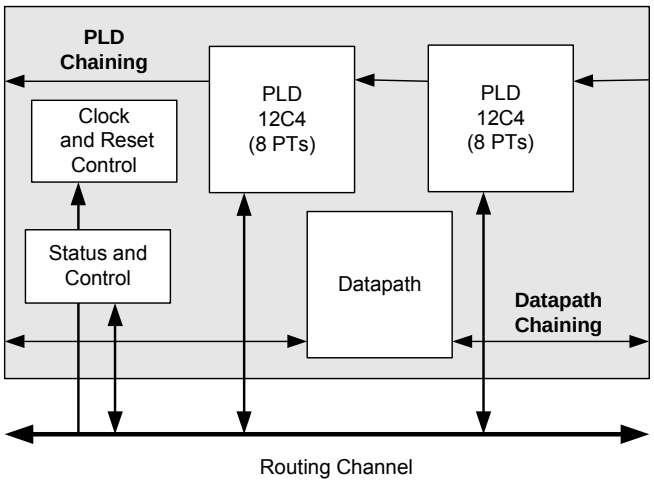
  Note IPOR disables the watchdog function. The program must enable the watchdog function at an appropriate point in the code by setting a register bit. When this bit is set, it cannot be cleared again except by an IPOR power on reset event.

7.2 Universal Digital Block

The UDB represents an evolutionary step to the next generation of PSoC embedded digital peripheral functionality. The architecture in first generation PSoC digital blocks provides coarse programmability in which a few fixed functions with a small number of options are available. The new UDB architecture is the optimal balance between configuration granularity and efficient implementation. A cornerstone of this approach is to provide the ability to customize the devices digital operation to match application requirements.

To achieve this, UDBs consist of a combination of uncommitted logic (PLD), structured logic (Datapath), and a flexible routing scheme to provide interconnect between these elements, I/O connections, and other peripherals. UDB functionality ranges from simple self contained functions that are implemented in one UDB, or even a portion of a UDB (unused resources are available for other functions), to more complex functions that require multiple UDBs. Examples of basic functions are timers, counters, CRC generators, PWMs, dead band generators, and communications functions, such as UARTs, SPI, and I^2C. Also, the PLD blocks and connectivity provide full featured general purpose programmable logic within the limits of the available resources.

Figure 7-2. UDB Block Diagram



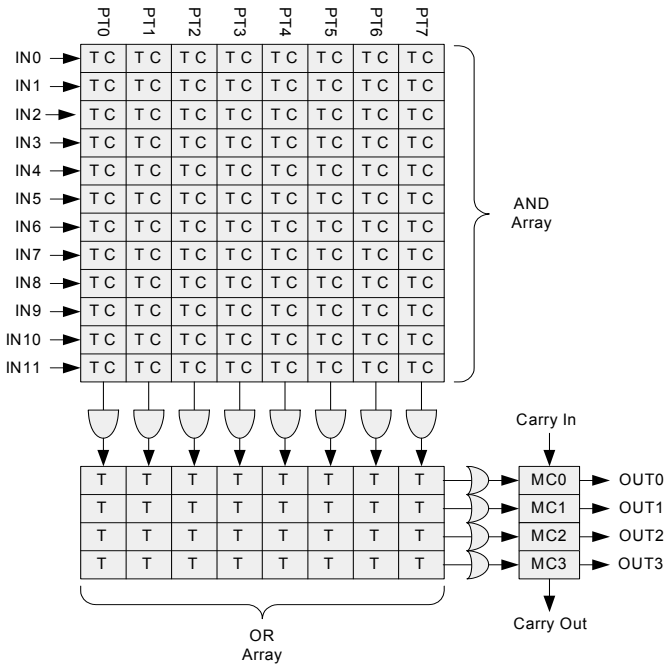
The main component blocks of the UDB are:

- PLD blocks – There are two small PLDs per UDB. These blocks take inputs from the routing array and form registered or combinational sum-of-products logic. PLDs are used to implement state machines, state bits, and combinational logic equations. PLD configuration is automatically generated from graphical primitives.
- Datapath module – This 8-bit wide datapath contains structured logic to implement a dynamically configurable ALU, a variety of compare configurations and condition generation. This block also contains input/output FIFOs, which are the primary parallel data interface between the CPU/DMA system and the UDB.
- Status and control module – The primary role of this block is to provide a way for CPU firmware to interact and synchronize with UDB operation.
- Clock and reset module – This block provides the UDB clocks and reset selection and control.

7.2.1 PLD Module

The primary purpose of the PLD blocks is to implement logic expressions, state machines, sequencers, lookup tables, and decoders. In the simplest use model, consider the PLD blocks as a standalone resource onto which general purpose RTL is synthesized and mapped. The more common and efficient use model is to create digital functions from a combination of PLD and datapath blocks, where the PLD implements only the random logic and state portion of the function while the datapath (ALU) implements the more structured elements.

Figure 7-3. PLD 12C4 Structure

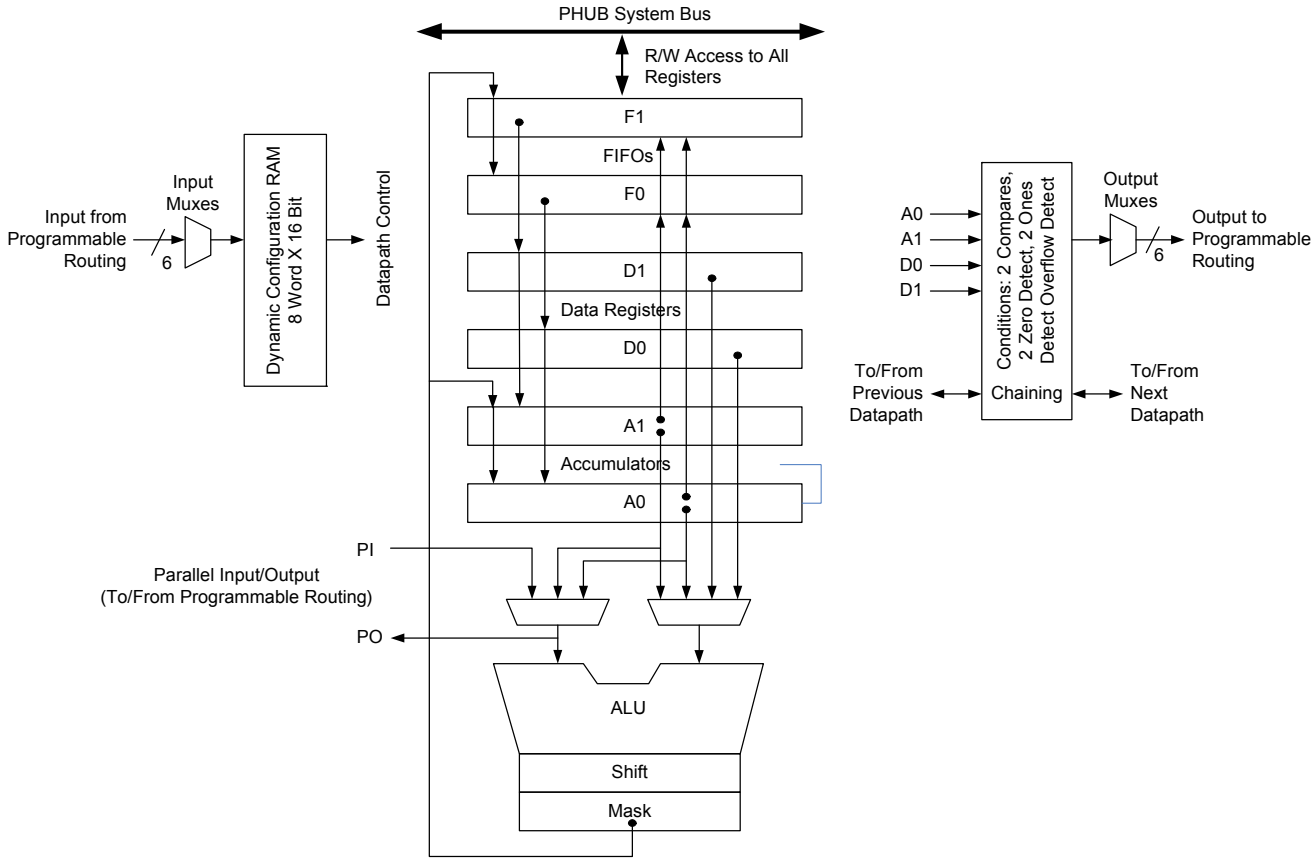


One 12C4 PLD block is shown in Figure 7-3. This PLD has 12 inputs, which feed across eight product terms. Each product term (AND function) can be from 1 to 12 inputs wide, and in a given product term, the true (T) or complement (C) of each input can be selected. The product terms are summed (OR function) to create the PLD outputs. A sum can be from 1 to 8 product terms wide. The 'C' in 12C4 indicates that the width of the OR gate (in this case 8) is constant across all outputs (rather than variable as in a 22V10 device). This PLA like structure gives maximum flexibility and insures that all inputs and outputs are permutable for ease of allocation by the software tools. There are two 12C4 PLDs in each UDB.

7.2.2 Datapath Module

The datapath contains an 8-bit single cycle ALU, with associated compare and condition generation logic. This datapath block is optimized to implement embedded functions, such as timers, counters, integrators, PWMs, PRS, CRC, shifters and dead band generators and many others.

Figure 7-4. Datapath Top Level



7.2.2.1 Working Registers

The datapath contains six primary working registers, which are accessed by CPU firmware or DMA during normal operation.

Table 7-1. Working Datapath Registers

Name	Function	Description
A0 and A1	Accumulators	These are sources and sinks for the ALU and also sources for the compares.
D0 and D1	Data Registers	These are sources for the ALU and sources for the compares.
F0 and F1	FIFOs	These are the primary interface to the system bus. They can be a data source for the data registers and accumulators or they can capture data from the accumulators or ALU. Each FIFO is four bytes deep.

7.2.2.2 Dynamic Configuration RAM

Dynamic configuration is the ability to change the datapath function and internal configuration on a cycle-by-cycle basis, under sequencer control. This is implemented using the 8-word × 16-bit configuration RAM, which stores eight unique 16-bit wide configurations. The address input to this RAM controls the sequence, and can be routed from any block connected to the UDB routing matrix, most typically PLD logic, I/O pins, or from the outputs of this or other datapath blocks.

ALU

The ALU performs eight general purpose functions. They are:

- Increment
- Decrement
- Add
- Subtract
- Logical AND
- Logical OR
- Logical XOR
- Pass, used to pass a value through the ALU to the shift register, mask, or another UDB register.

9.2 Serial Wire Debug Interface

The SWD interface is the preferred alternative to the JTAG interface. It requires only two pins instead of the four or five needed by JTAG. SWD provides all of the programming and debugging features of JTAG at the same speed. SWD does not provide access to scan chains or device chaining. The SWD clock frequency can be up to 1/3 of the CPU clock frequency.

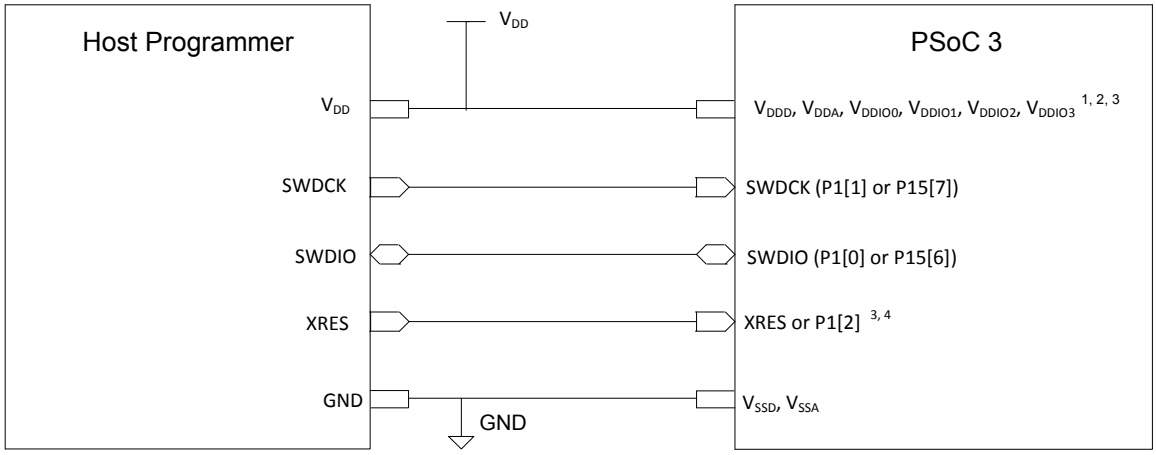
SWD uses two pins, either two of the JTAG pins (TMS and TCK) or the USBIO D+ and D– pins. The USBIO pins are useful for in system programming of USB solutions that would otherwise require a separate programming connector. One pin is used for the data clock and the other is used for data input and output.

SWD can be enabled on only one of the pin pairs at a time. This only happens if, within 8 µs (key window) after reset, that pin pair (JTAG or USB) receives a predetermined acquire sequence of 1s and 0s. If the NVL latches are set for SWD (see *Section 5.5*), this sequence need not be applied to the JTAG pin pair. The acquire sequence must always be applied to the USB pin pair.

SWD is used for debugging or for programming the flash memory.

The SWD interface can be enabled from the JTAG interface or disabled, allowing its pins to be used as GPIO. Unlike JTAG, the SWD interface can always be reacquired on any device during the key window. It can then be used to reenable the JTAG interface, if desired. When using SWD or JTAG pins as standard GPIO, make sure that the GPIO functionality and PCB circuits do not interfere with SWD or JTAG use.

Figure 9-2. SWD Interface Connections between PSoC 3 and Programmer



[1] The voltage levels of the Host Programmer and the PSoC 3 voltage domains involved in Programming should be the same. XRES pin (XRES_N or P1[2]) is powered by V_{DDIO1}. The USB SWD pins are powered by V_{DDD}. So for Programming using the USB SWD pins with XRES pin, the V_{DDD}, V_{DDIO1} of PSoC 3 should be at the same voltage level as Host V_{DD}. Rest of PSoC 3 voltage domains (V_{DDA}, V_{DDIO0}, V_{DDIO2}, V_{DDIO3}) need not be at the same voltage level as host Programmer. The Port 1 SWD pins are powered by V_{DDIO1}. So V_{DDIO1} of PSoC 3 should be at same voltage level as host V_{DD} for Port 1 SWD programming. Rest of PSoC 3 voltage domains (V_{DDD}, V_{DDA}, V_{DDIO0}, V_{DDIO2}, V_{DDIO3}) need not be at the same voltage level as host Programmer.

[2] Vdda must be greater than or equal to all other power supplies (Vddd, Vddio's) in PSoC 3.

[3] For Power cycle mode Programming, XRES pin is not required. But the Host programmer must have the capability to toggle power (Vddd, Vdda, All Vddio's) to PSoC 3. This may typically require external interface circuitry to toggle power which will depend on the programming setup. The power supplies can be brought up in any sequence, however, once stable, VDDA must be greater than or equal to all other supplies.

[4] P1[2] will be configured as XRES by default only for 48-pin devices (without dedicated XRES pin). For devices with dedicated XRES pin, P1[2] is GPIO pin by default. So use P1[2] as Reset pin only for 48-pin devices, but use dedicated XRES pin for rest of devices.

9.3 Debug Features

Using the JTAG or SWD interface, the CY8C38 supports the following debug features:

- Halt and single-step the CPU
- View and change CPU and peripheral registers, and RAM addresses
- Eight program address breakpoints
- One memory access breakpoint—break on reading or writing any memory address and data value
- Break on a sequence of breakpoints (non recursive)
- Debugging at the full speed of the CPU
- Compatible with PSoC Creator and MiniProg3 programmer and debugger
- Standard JTAG programming and debugging interfaces make CY8C38 compatible with other popular third-party tools (for example, ARM / Keil)

9.4 Trace Features

The CY8C38 supports the following trace features when using JTAG or SWD:

- Trace the 8051 program counter (PC), accumulator register (ACC), and one SFR / 8051 core RAM register
- Trace depth up to 1000 instructions if all registers are traced, or 2000 instructions if only the PC is traced (on devices that include trace memory)
- Program address trigger to start tracing
- Trace windowing, that is, only trace when the PC is within a given range
- Two modes for handling trace buffer full: continuous (overwriting the oldest trace data) or break when trace buffer is full

9.5 Single Wire Viewer Interface

The SWV interface is closely associated with SWD but can also be used independently. SWV data is output on the JTAG interface's TDO pin. If using SWV, you must configure the device for SWD, not JTAG. SWV is not supported with the JTAG interface.

SWV is ideal for application debug where it is helpful for the firmware to output data similar to 'printf' debugging on PCs. The SWV is ideal for data monitoring, because it requires only a single pin and can output data in standard UART format or Manchester encoded format. For example, it can be used to tune a PID control loop in which the output and graphing of the three error terms greatly simplifies coefficient tuning.

The following features are supported in SWV:

- 32 virtual channels, each 32 bits long
- Simple, efficient packing and serializing protocol
- Supports standard UART format (N81)

9.6 Programming Features

The JTAG and SWD interfaces provide full programming support. The entire device can be erased, programmed, and verified. You can increase flash protection levels to protect firmware IP. Flash protection can only be reset after a full device erase. Individual flash blocks can be erased, programmed, and verified, if block security settings permit.

9.7 Device Security

PSoC 3 offers an advanced security feature called device security, which permanently disables all test, programming, and debug ports, protecting your application from external access. The device security is activated by programming a 32-bit key (0×50536F43) to a Write Once Latch (WOL).

The Write Once Latch is a type of nonvolatile latch (NVL). The cell itself is an NVL with additional logic wrapped around it. Each WOL device contains four bytes (32 bits) of data. The wrapper outputs a '1' if a super-majority (28 of 32) of its bits match a pre-determined pattern (0×50536F43); it outputs a '0' if this majority is not reached. When the output is 1, the Write Once NV latch locks the part out of Debug and Test modes; it also permanently gates off the ability to erase or alter the contents of the latch. Matching all bits is intentionally not required, so that single (or few) bit failures do not deassert the WOL output. The state of the NVL bits after wafer processing is truly random with no tendency toward 1 or 0.

The WOL only locks the part after the correct 32-bit key (0×50536F43) is loaded into the NVL's volatile memory, programmed into the NVL's nonvolatile cells, and the part is reset. The output of the WOL is only sampled on reset and used to disable the access. This precaution prevents anyone from reading, erasing, or altering the contents of the internal memory.

The user can write the key into the WOL to lock out external access only if no flash protection is set (see "Flash Security" on page 23). However, after setting the values in the WOL, a user still has access to the part until it is reset. Therefore, a user can write the key into the WOL, program the flash protection data, and then reset the part to lock it.

If the device is protected with a WOL setting, Cypress cannot perform failure analysis and, therefore, cannot accept RMAs from customers. The WOL can be read out through the SWD port to electrically identify protected parts. The user can write the key in WOL to lock out external access only if no flash protection is set. For more information on how to take full advantage of the security features in PSoC see the PSoC 3 TRM.

Disclaimer

Note the following details of the flash code protection features on Cypress devices.

Cypress products meet the specifications contained in their particular Cypress data sheets. Cypress believes that its family of products is one of the most secure families of its kind on the market today, regardless of how they are used. There may be methods, unknown to Cypress, that can breach the code protection features. Any of these methods, to our knowledge, would be dishonest and possibly illegal. Neither Cypress nor any other semiconductor manufacturer can guarantee the security of their code. Code protection does not mean that we are guaranteeing the product as "unbreakable."

Cypress is willing to work with the customer who is concerned about the integrity of their code. Code protection is constantly evolving. We at Cypress are committed to continuously improving the code protection features of our products.

9.8 CSP Package Bootloader

A factory-installed bootloader program is included in all devices with CSP packages. The bootloader is compatible with PSoC Creator 3.0 bootloadable project files and has the following features:

- I^2C-based
- SCLK and SDAT available at P1[6] and P1[7], respectively
- External pull-up resistors required
- I^2C slave, address 4, data rate = 100 kbps
- Single application
- Wait two seconds for bootload command
- Other bootloader options are as set by the PSoC Creator 3.0 Bootloader Component default
- Occupies the bottom 9K of flash

For more information on this bootloader, see the following Cypress application notes:

- AN89611 – PSoC® 3 AND PSoC 5LP - Getting Started With Chip Scale Packages (CSP)
- AN73854 – PSoC 3 and PSoC 5 LP Introduction to Bootloaders
- AN60317 – PSoC 3 and PSoC 5 LP I^2C Bootloader

Note that a PSOC Creator bootloadable project must be associated with .hex and .elf files for a bootloader project that is configured for the target device. Bootloader .hex and .elf files can be found at www.cypress.com/go/PSoC3datasheet.

The factory-installed bootloader can be overwritten using JTAG or SWD programming.

11. Electrical Specifications

Specifications are valid for –40 °C ≤ T_A ≤ 85 °C and T_J ≤ 100 °C, except where noted. Specifications are valid for 1.71 V to 5.5 V, except where noted. The unique flexibility of the PSoC UDBs and analog blocks enable many functions to be implemented in PSoC Creator components, see the component data sheets for full AC/DC specifications of individual functions. See the "Example Peripherals" section on page 44 for further explanation of PSoC Creator components.

11.1 Absolute Maximum Ratings

Table 11-1. Absolute Maximum Ratings DC Specifications[18]

Parameter	Description	Conditions	Min	Typ	Max	Units
V_{DDA}	Analog supply voltage relative to V_{SSA}		–0.5	–	6	V
V_{DDD}	Digital supply voltage relative to V_{SSD}		–0.5	–	6	V
V_{DDIO}	I/O supply voltage relative to V_{SSD}		–0.5	–	6	V
V_{CCA}	Direct analog core voltage input		–0.5	–	1.95	V
V_{CCD}	Direct digital core voltage input		–0.5	–	1.95	V
V_{SSA}	Analog ground voltage		V_{SSD} – 0.5	–	V_{SSD} + 0.5	V
V_{GPIO}[19]	DC input voltage on GPIO	Includes signals sourced by V_{DDA} and routed internal to the pin	V_{SSD} – 0.5	–	V_{DDIO} + 0.5	V
V_{SIO}	DC input voltage on SIO	Output disabled	V_{SSD} – 0.5	–	7	V
		Output enabled	V_{SSD} – 0.5	–	6	V
V_{IND}	Voltage at boost converter input		0.5	–	5.5	V
V_{BAT}	Boost converter supply		V_{SSD} – 0.5	–	5.5	V
I_{VDDIO}	Current per V_{DDIO} supply pin		–	–	100	mA
I_{GPIO}	GPIO current		–30	–	41	mA
I_{SIO}	SIO current		–49	–	28	mA
I_{USBIO}	USBIO current		–56	–	59	mA
V_{EXTREF}	ADC external reference inputs	Pins P0[3], P3[2]	–	–	2	V
LU	Latch up current[20]		–140	–	140	mA
ESD_{HBM}	Electrostatic discharge voltage, Human body model	V_{SSA} tied to V_{SSD}	2200	–	–	V
		V_{SSA} not tied to V_{SSD}	750	–	–	V
ESD_{CDM}	Electrostatic discharge voltage, Charge device model		500	–	–	V

Notes

18. Usage above the absolute maximum conditions listed in Table 11-1 may cause permanent damage to the device. Exposure to Absolute Maximum conditions for extended periods of time may affect device reliability. The Maximum Storage Temperature is 150 °C in compliance with JEDEC Standard JESD22-A103, High Temperature Storage Life. When used below Absolute Maximum conditions but above normal operating conditions, the device may not operate to specification.
19. The V_{DDIO} supply voltage must be greater than the maximum voltage on the associated GPIO pins. Maximum voltage on GPIO pin ≤ V_{DDIO} ≤ V_{DDA}.
20. Meets or exceeds JEDEC Spec EIA/JESD78 IC Latch-up Test.

Table 11-7. Recommended External Components for Boost Circuit

Parameter	Description	Conditions	Min	Typ	Max	Units
L_{BOOST}	Boost inductor	4.7 µH nominal	3.7	4.7	5.7	µH
		10 µH nominal	8.0	10.0	12.0	µH
		22 µH nominal	17.0	22.0	27.0	µH
C_{BOOST}	Total capacitance sum of V_{DDD}, V_{DDA}, V_{DDIO}[37]		17.0	26.0	31.0	µF
C_{BAT}	Battery filter capacitor		17.0	22.0	27.0	µF
I_F	Schottky diode average forward current		1.0	–	–	A
V_R	Schottky reverse voltage		20.0	–	–	V

Figure 11-8. T_A range over V_{BAT} and V_{OUT}

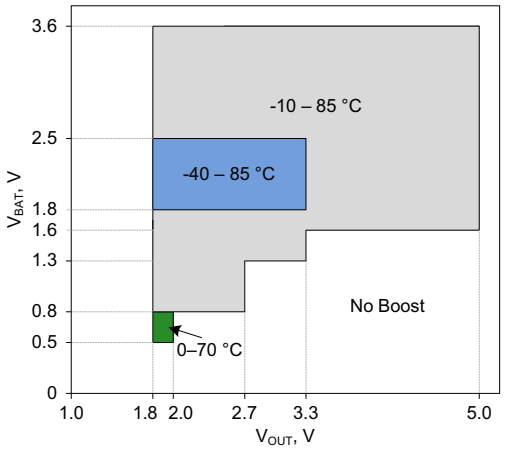


Figure 11-9. I_{OUT} range over V_{BAT} and V_{OUT}

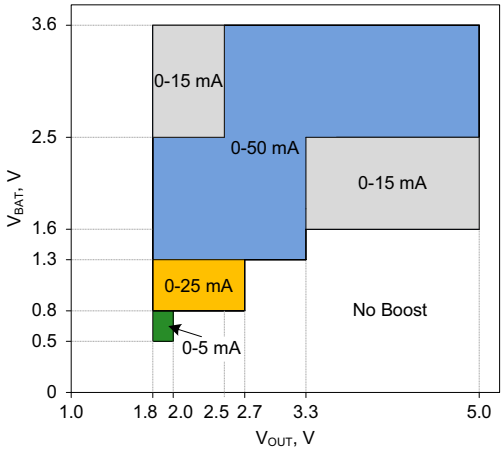
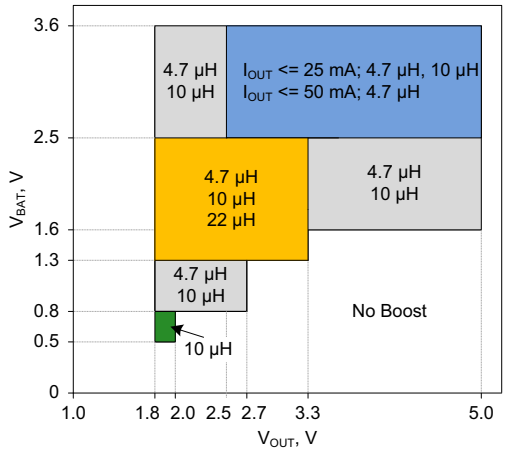


Figure 11-10. L_{BOOST} values over V_{BAT} and V_{OUT}



Note
37. Based on device characterization (Not production tested).

Figure 11-11. Efficiency vs V_{BAT}, L_{BOOST} = 4.7 µH [38]

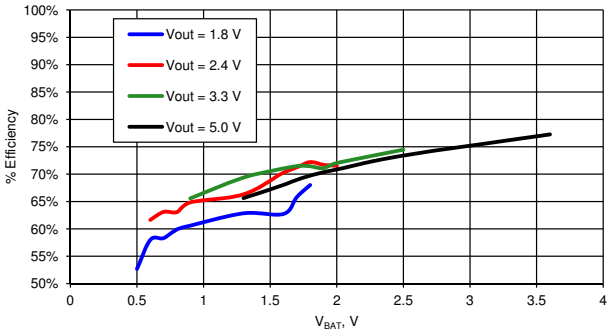


Figure 11-12. Efficiency vs V_{BAT}, L_{BOOST} = 10 µH [38]

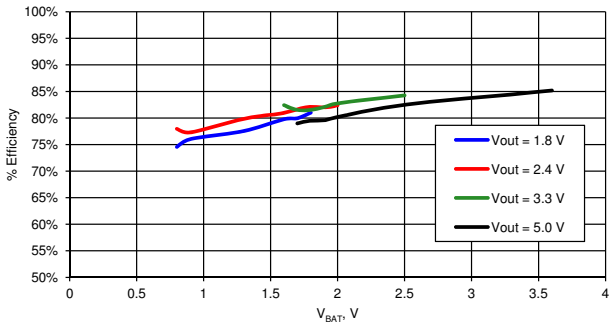


Figure 11-13. Efficiency vs V_{BAT}, L_{BOOST} = 22 µH [38]

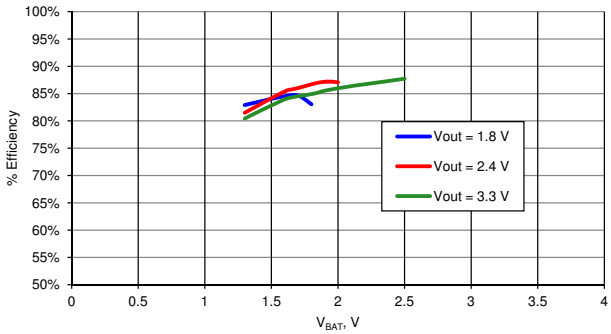
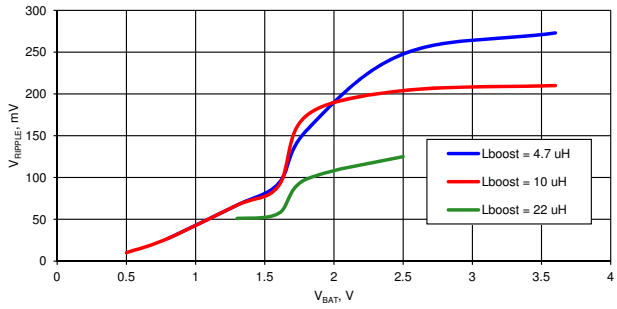


Figure 11-14. V_{RIPPLE} vs V_{BAT} [38]



Note
38. Typical example. Actual values may vary depending on external component selection, PCB layout, and other design parameters.

.

Table 11-20. Opamp AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
GBW	Gain-bandwidth product	Power mode = minimum, 15 pF load	1	–	–	MHz
		Power mode = low, 15 pF load	2	–	–	MHz
		Power mode = medium, 200 pF load	1	–	–	MHz
		Power mode = high, 200 pF load	3	–	–	MHz
SR	Slew rate, 20% - 80%	Power mode = low, 15 pF load	1.1	–	–	V/µs
		Power mode = medium, 200 pF load	0.9	–	–	V/µs
		Power mode = high, 200 pF load	3	–	–	V/µs
e_n	Input noise density	Power mode = high, V_{DDA} = 5 V, at 100 kHz	–	45	–	nV/sqrtHz

Figure 11-30. Opamp Noise vs Frequency, Power Mode = High, V_{DDA} = 5V

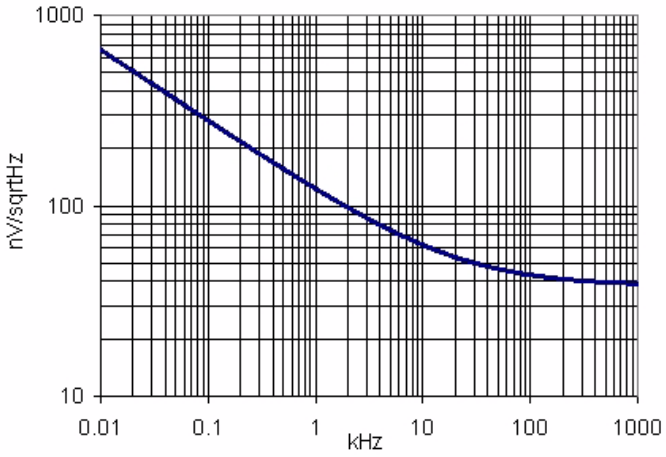


Figure 11-31. Opamp Step Response, Rising

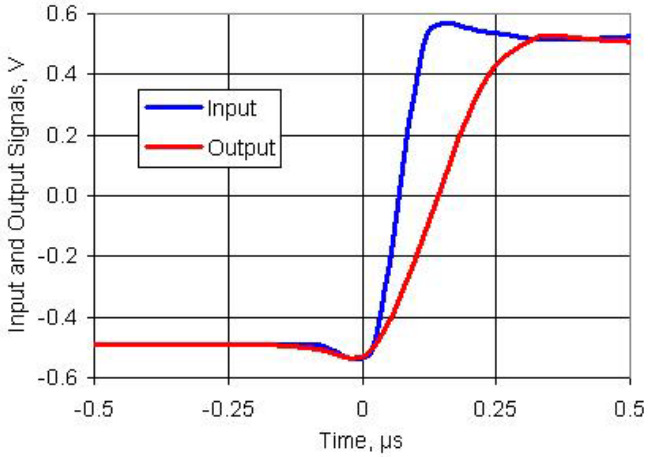


Figure 11-32. Opamp Step Response, Falling

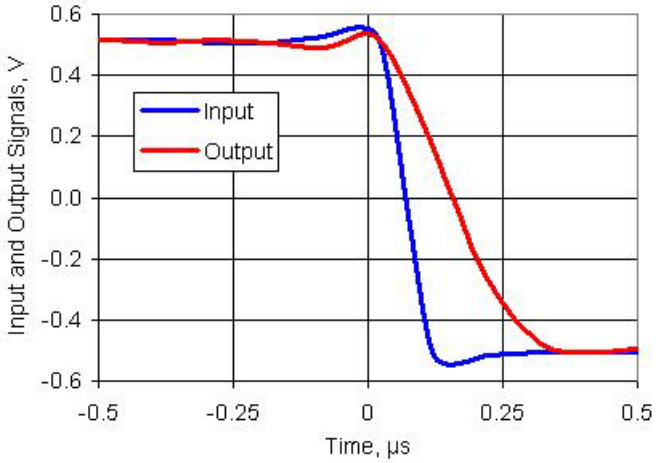


Table 11-23. Delta-sigma ADC Sample Rates, Range = ±1.024 V

Resolution, Bits	Continuous		Multi-Sample		Multi-Sample Turbo	
	Min	Max	Min	Max	Min	Max
8	8000	384000	1911	91701	1829	87771
9	6400	307200	1543	74024	1489	71441
10	5566	267130	1348	64673	1307	62693
11	4741	227555	1154	55351	1123	53894
12	4000	192000	978	46900	956	45850
13	3283	157538	806	38641	791	37925
14	2783	133565	685	32855	674	32336
15	2371	113777	585	28054	577	27675
16	2000	48000	495	11861	489	11725
17	500	12000	124	2965	282	6766
18	125	3000	31	741	105	2513
19	16	375	4	93	15	357
20	8	187.5	2	46	8	183

Figure 11-33. Delta-sigma ADC IDD vs sps, Range = ±1.024 V, Continuous Sample Mode, Input Buffer Bypassed

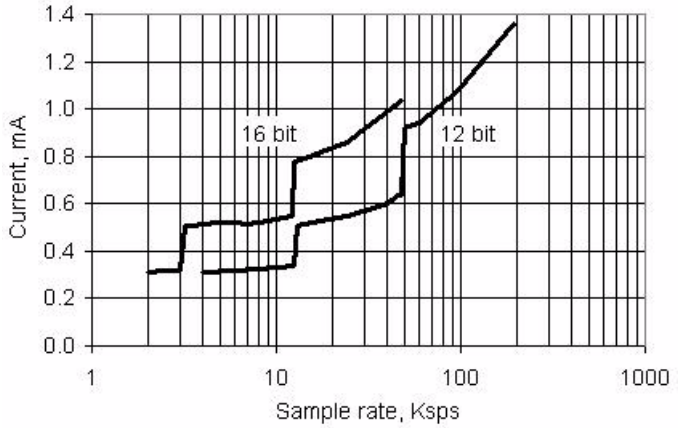


Figure 11-34. Delta-sigma ADC Noise Histogram, 1000 Samples, 20-Bit, 187 sps, Ext Ref, $V_{IN} = V_{REF}/2$, Range = ±1.024 V

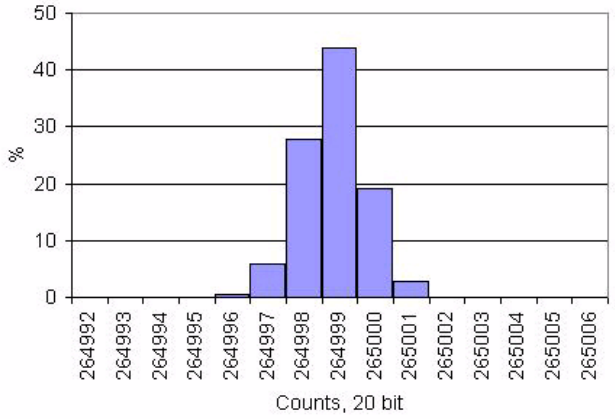


Figure 11-35. Delta-sigma ADC Noise Histogram, 1000 Samples, 16-bit, 48 ksps, Ext Ref, $V_{IN} = V_{REF}/2$, Range = ±1.024 V

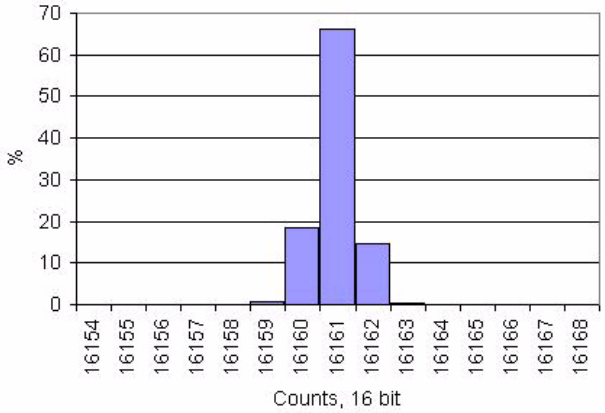


Figure 11-36. Delta-sigma ADC Noise Histogram, 1000 Samples, 16-bit, 48 ksps, Int Ref, $V_{IN} = V_{REF}/2$, Range = ±1.024 V

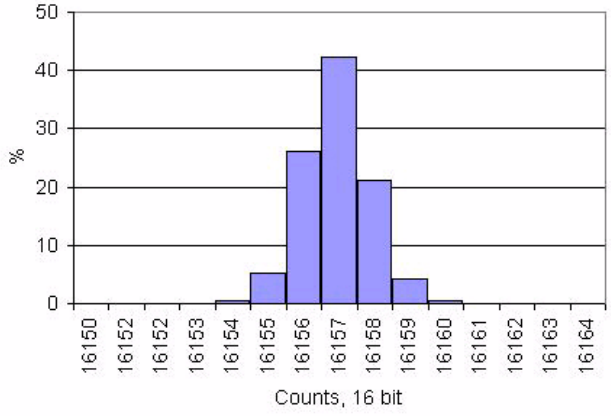


Figure 11-49. IDAC Operating Current vs Temperature, Range = 255 µA, Code = 0, Source Mode

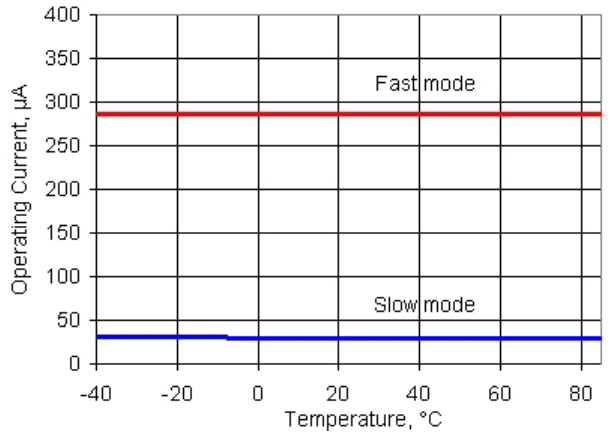


Figure 11-50. IDAC Operating Current vs Temperature, Range = 255 µA, Code = 0, Sink Mode

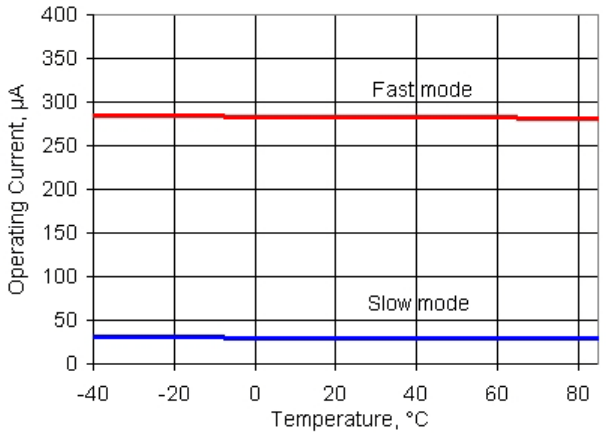


Table 11-33. IDAC AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
F_{DAC}	Update rate		–	–	8	Msps
T_{SETTLE}	Settling time to 0.5 LSB	Range = 31.875 µA or 255 µA, full scale transition, High speed mode, 600 Ω 15-pF load	–	–	125	ns
	Current noise	Range = 255 µA, source mode, High speed mode, V_{DDA} = 5 V, 10 kHz	–	340	–	pA/sqrtHz

Figure 11-51. IDAC Step Response, Codes 0x40 - 0xC0, 255 µA Mode, Source Mode, High speed mode, V_{DDA} = 5 V

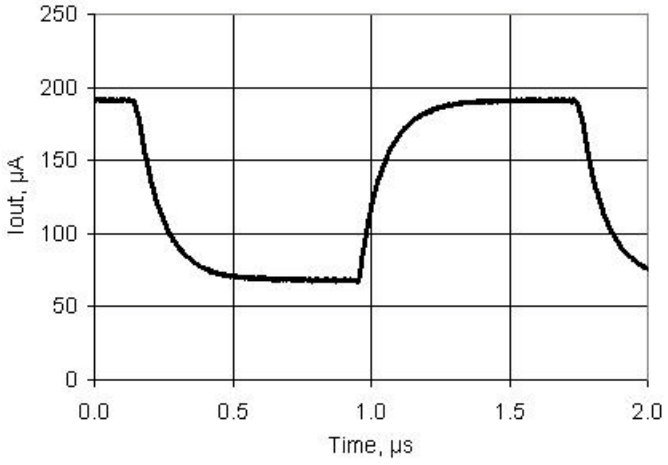
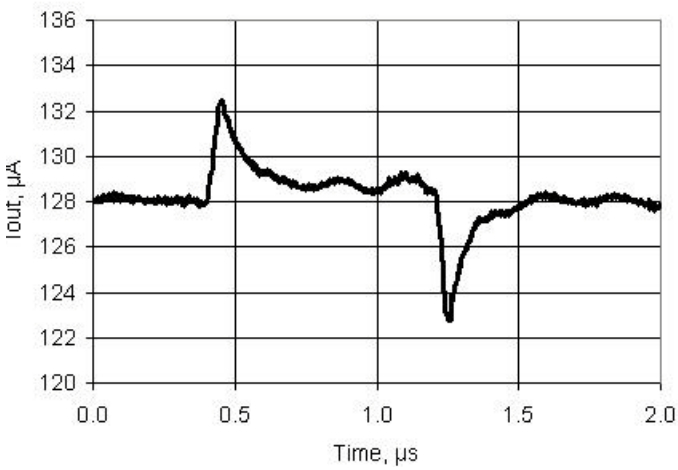


Figure 11-52. IDAC Glitch Response, Codes 0x7F - 0x80, 255 µA Mode, Source Mode, High speed mode, V_{DDA} = 5 V



11.8.5 SWD Interface

Figure 11-74. SWD Interface Timing

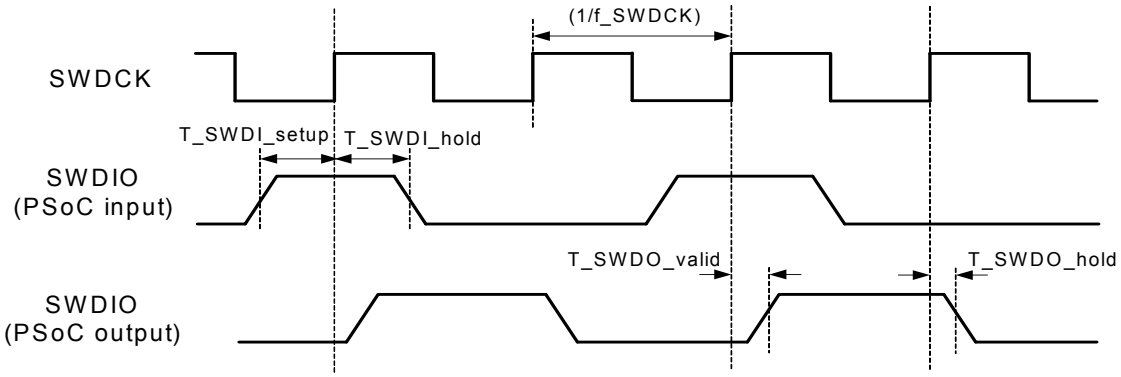


Table 11-75. SWD Interface AC Specifications[71]

Parameter	Description	Conditions	Min	Typ	Max	Units
f_SWDCK	SWDCLK frequency	3.3 V ≤ V_{DDD} ≤ 5 V	–	–	14[72]	MHz
		1.71 V ≤ V_{DDD} < 3.3 V	–	–	7[72]	MHz
		1.71 V ≤ V_{DDD} < 3.3 V, SWD over USBIO pins	–	–	5.5[72]	MHz
T_SWDI_setup	SWDIO input setup before SWDCK high	T = 1/f_SWDCK max	T/4	–	–	
T_SWDI_hold	SWDIO input hold after SWDCK high	T = 1/f_SWDCK max	T/4	–	–	
T_SWDO_valid	SWDCK high to SWDIO output	T = 1/f_SWDCK max	–	–	2T/5	

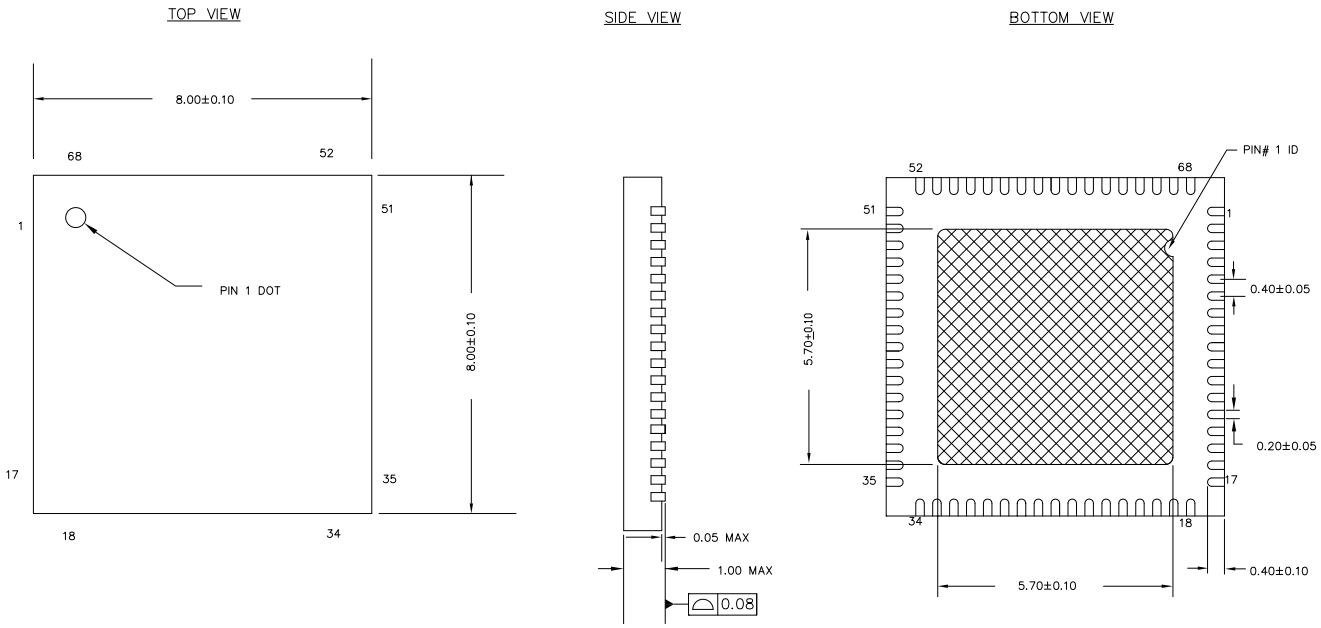
11.8.6 SWV Interface

Table 11-76. SWV Interface AC Specifications[71]

Parameter	Description	Conditions	Min	Typ	Max	Units
	SWV mode SWV bit rate		–	–	33	Mbit

Notes
71. Based on device characterization (Not production tested).
72. f_SWDCK must also be no more than 1/3 CPU clock frequency.

Figure 13-3. 68-pin QFN 8×8 with 0.4 mm Pitch Package Outline (Sawn Version)

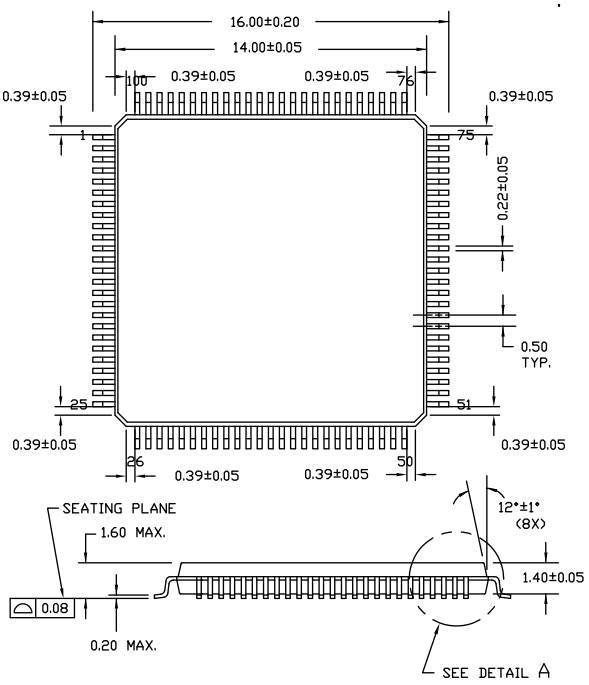


NOTES:

1. HATCH AREA IS SOLDERABLE EXPOSED METAL.
2. REFERENCE JEDEC#: MO−220
3. PACKAGE WEIGHT: 17 ± 2mg
4. ALL DIMENSIONS ARE IN MILLIMETERS

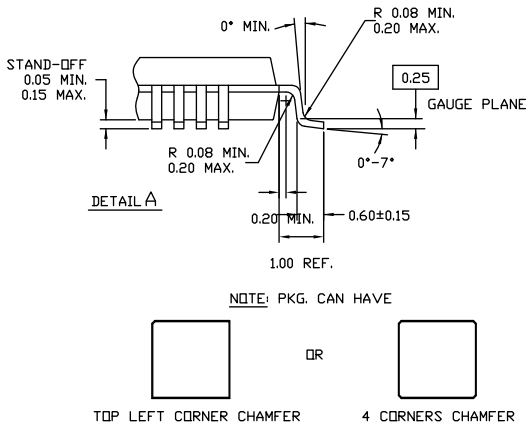
001-09618 *E

Figure 13-4. 100-pin TQFP (14 × 14 × 1.4 mm) Package Outline



NOTE:

1. JEDEC STD REF MS-026
2. BODY LENGTH DIMENSION DOES NOT INCLUDE MOLD PROTRUSION/END FLASH
   MOLD PROTRUSION/END FLASH SHALL NOT EXCEED 0.0098 in (0.25 mm) PER SIDE
   BODY LENGTH DIMENSIONS ARE MAX PLASTIC BODY SIZE INCLUDING MOLD MISMATCH
3. DIMENSIONS IN MILLIMETERS



51-85048 *J

Description Title: PSoC® 3: CY8C38 Family Datasheet Programmable System-on-Chip (PSoC®) *(continued)* Document Number: 001-11729				
Revision	**ECN**	**Submission Date**	**Orig. of Change**	**Description of Change**
*K	2903576	04/01/2010	MKEA	Updated Vb pin in PCB Schematic. Updated Tstartup parameter in AC Specifications table. Added Load regulation and Line regulation parameters to Inductive Boost Regulator DC Specifications table. Updated I_{CC} parameter in LCD Direct Drive DC Specs table. In page 1, updated internal oscillator range under Precision programmable clocking to start from 3 MHz. Updated I_{OUT} parameter in LCD Direct Drive DC Specs table. Updated Table 6-2 and Table 6-3. Added bullets on CapSense in page 1; added CapSense column in Section 12. Removed some references to footnote [1]. Changed INC_Rn cycles from 3 to 2 (Table 4-1). Added footnote in PLL AC Specification table. Added PLL intermediate frequency row with footnote in PLL AC Specs table. Added UDBs subsection under 11.6 Digital Peripherals. Updated Figure 2-6 (PCB Layout). Updated Pin Descriptions section and modified Figures 6-6, 6-8, 6-9. Updated LVD in Tables 6-2 and 6-3; modified Low-power modes bullet in page 1. Added note to Figures 2-5 and 6-2; Updated Figure 6-2 to add capacitors for V_{DDA} and V_{DDD} pins. Updated boost converter section (6.2.2). Updated Tstartup values in Table 11-3. Removed IPOR rows from Table 11-68. Updated 6.3.1.1, Power Voltage Level Monitors. Updated section 5.2 and Table 11-2 to correct suggestion of execution from flash. Updated V_{REF} specs in Table 11-21. Updated IDAC uncompensated gain error in Table 11-25. Updated Delay from Interrupt signal input to ISR code execution from ISR code in Table11-72. Removed other line in table. Added sentence to last paragraph of section 6.1.1.3. Updated T_{RESP}, high and low-power modes, in Table 11-24. Updated f_TCK values in Table 11-73 and f_SWDCK values in Table 11-74. Updated SNR condition in Table 11-20. Corrected unit of measurement in Table 11-21. Updated sleep wakeup time in Table 6-3 and Tsleep in Table 11-3. Added 1.71 V <= V_{DDD} < 3.3 V, SWD over USBIO pins value to Table 11-74. Removed mention of hibernate reset (HRES) from page 1 features, Table 6-3, Section 6.2.1.4, Section 6.3, and Section 6.3.1.1. Changed PPOR/PRES to TBDs in Section 6.3.1.1, Section 6.4.1.6 (changed PPOR to reset), Table 11-3 (changed PPOR to PRES), Table 11-68 (changed title, values TBD), and Table 11-69 (changed PPOR_TR to PRES_TR). Added sentence saying that LVD circuits can generate a reset to Section 6.3.1.1. Changed I_{DD} values on page 1, page 5, and Table 11-2. Changed resume time value in Section 6.2.1.3. Changed ESD HBM value in Table 11-1. Changed SNR in 16-bit resolution mode value and sample rate row in Table 11-20. Removed V_{DDA} = 1.65 V rows and changed BWag value in Table 11-22. Changed V_{IOFF} values and changed CMRR value in Table 11-23. Changed INL max value in Table 11-27. Added max value to the Quiescent current specs in Tables 11-29 and 11-31. Changed occurrences of “Block” to “Row” and deleted the “ECC not included” footnote in Table 11-57. Changed max response time value in Tables 11-69 and 11-71. Changed the Startup time in Table 11-79. Added condition to intermediate frequency row in Table 11-85. Added row to Table 11-69. Added brown out note to Section 11.8.1.